#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Rule 1.53(b) Divisional Application of USSN: 09/274,767

SHIMOYAMA, et al.

Group Art Unit: 2828 (expected)

Serial No.: Not Yet Assigned

Examiner: Quyen Phan Leung (expected)

Filed: Herewith

For.

SEMICONDUCTOR LIGHT-EMITTING DEVICE

# PURSUANT TO 37 CFR 1.97(b)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

September 2, 2003

Sir:

This Information Disclosure Statement is being filed in order to comply with Applicant's duty of disclosure under 37 CFR 1.56. The documents listed on the Form PTO-1449 were made of record in parent application Serial No. 09/274,767.

The Commissioner is authorized to charge our Deposit Account No. 01-2340 for any fee which is deemed by the Patent and Trademark Office to be required to effect consideration of this statement.

Respectfully submitted,

ARMSTRONG, WESTERMAN & HATTORI, LLP

Stephen G. Adrian Attorney for Applicants Reg. No. 32,878

SGA/rer Atty. Docket No. 990342A Suite 1000 1725 K Street, N.W. Washington, D.C. 20006

(202) 659-2930

Enclosure: PTO-1449

23850

2383U
PATENT TRADEMARK OFFICE

INFORMATION DISCLOSURE CITATION PTO-1449	Atty. Docket No. 990342A	Serial No. Not Yet Assigned	
	Applicant(s): SHIMOYAMA, et al.		
	Filing Date: September 2, 2003	Group Art Unit: 2828 (expected)	

### **U.S. PATENT DOCUMENTS**

Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
	AA	5,003,549	Mitsui et al.	3/1991	372	46	
	AB	5,465,266	Bour et al.	11/1995			
	AC	4,622,673	Tsang	11/1986	372	45	

## FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation (Yes or No)
 AD	EP 0 867 949	9/30/98	European	
 AE	EP 0 469 301	6/29/90	European	
 AF				

#### OTHER DOCUMENTS

	AG	LIN J-F ET AL: "High temperature and low threshold current operation of strained AlGaInP/Ga0.4In0.6P multiple quantum well laser diodes emitting at 676 nm" vol. 30, no. 6, pages 494-495, March 1994.
	АН	Patent Abstracts of Japan; vol. 017, no. 065 (E-1317); February 9, 1993 & JP 04 269886 A (Toshiba Corp.), 9/25/92).
	AI	Patent Abstracts of Japan; vol. 1997, no. 11, November 28, 1997 & JP 09 199791 A (NNEC Corp), July 31, 1997
Examiner	1	Date Considered